

Search Notes**Application/Control No.**

10/585,863

Examiner

YONG D. PAK

**Applicant(s)/Patent under
Reexamination**

GAO ET AL.

Art Unit

1652

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
stic: seq id no:2 and 9, see SCORE	6/11/2009	YP
EAST (all databases): text & inventor search, see search history	6/11/2009	YP
PALM: search of all inventors	6/11/2009	YP